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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

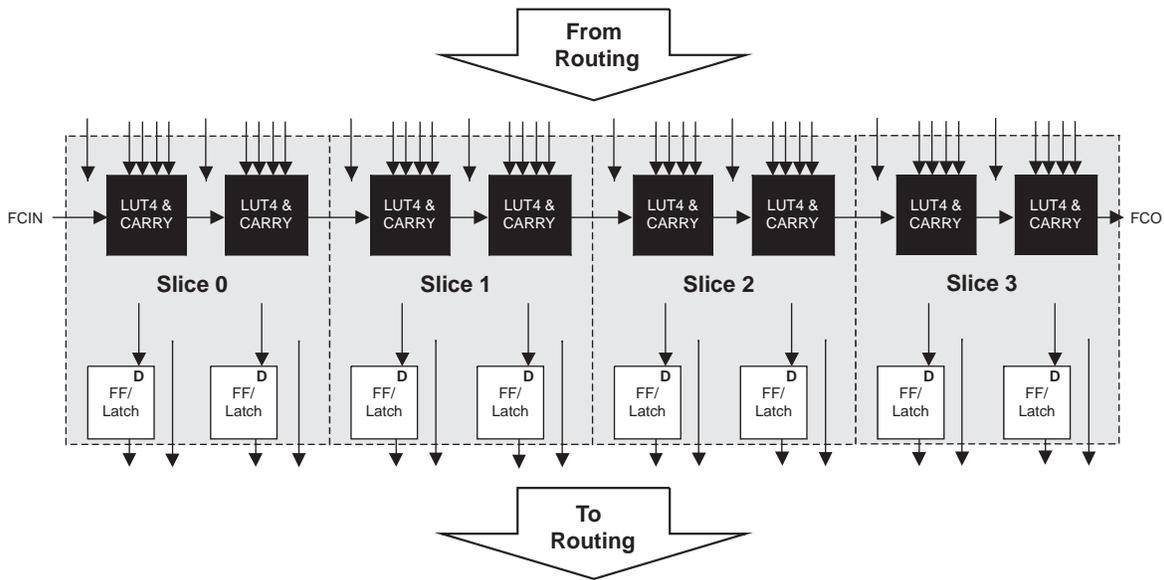
Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	540
Number of Logic Elements/Cells	4320
Total RAM Bits	94208
Number of I/O	206
Number of Gates	-
Voltage - Supply	2.375V ~ 3.465V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (Tj)
Package / Case	256-LBGA
Supplier Device Package	256-FTBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmx02-4000hc-6ftg256i

Figure 2-3. PFU Block Diagram



Slices

Slices 0-3 contain two LUT4s feeding two registers. Slices 0-2 can be configured as distributed memory. Table 2-1 shows the capability of the slices in PFU blocks along with the operation modes they enable. In addition, each PFU contains logic that allows the LUTs to be combined to perform functions such as LUT5, LUT6, LUT7 and LUT8. The control logic performs set/reset functions (programmable as synchronous/ asynchronous), clock select, chip-select and wider RAM/ROM functions.

Table 2-1. Resources and Modes Available per Slice

Slice	PFU Block	
	Resources	Modes
Slice 0	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM
Slice 1	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM
Slice 2	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM
Slice 3	2 LUT4s and 2 Registers	Logic, Ripple, ROM

Figure 2-4 shows an overview of the internal logic of the slice. The registers in the slice can be configured for positive/negative and edge triggered or level sensitive clocks. All slices have 15 inputs from routing and one from the carry-chain (from the adjacent slice or PFU). There are seven outputs: six for routing and one to carry-chain (to the adjacent PFU). Table 2-2 lists the signals associated with Slices 0-3.

Modes of Operation

Each slice has up to four potential modes of operation: Logic, Ripple, RAM and ROM.

Logic Mode

In this mode, the LUTs in each slice are configured as 4-input combinatorial lookup tables. A LUT4 can have 16 possible input combinations. Any four input logic functions can be generated by programming this lookup table. Since there are two LUT4s per slice, a LUT5 can be constructed within one slice. Larger look-up tables such as LUT6, LUT7 and LUT8 can be constructed by concatenating other slices. Note LUT8 requires more than four slices.

Ripple Mode

Ripple mode supports the efficient implementation of small arithmetic functions. In Ripple mode, the following functions can be implemented by each slice:

- Addition 2-bit
- Subtraction 2-bit
- Add/subtract 2-bit using dynamic control
- Up counter 2-bit
- Down counter 2-bit
- Up/down counter with asynchronous clear
- Up/down counter with preload (sync)
- Ripple mode multiplier building block
- Multiplier support
- Comparator functions of A and B inputs
 - A greater-than-or-equal-to B
 - A not-equal-to B
 - A less-than-or-equal-to B

Ripple mode includes an optional configuration that performs arithmetic using fast carry chain methods. In this configuration (also referred to as CCU2 mode) two additional signals, Carry Generate and Carry Propagate, are generated on a per-slice basis to allow fast arithmetic functions to be constructed by concatenating slices.

RAM Mode

In this mode, a 16x4-bit distributed single port RAM (SPR) can be constructed by using each LUT block in Slice 0 and Slice 1 as a 16x1-bit memory. Slice 2 is used to provide memory address and control signals.

MachXO2 devices support distributed memory initialization.

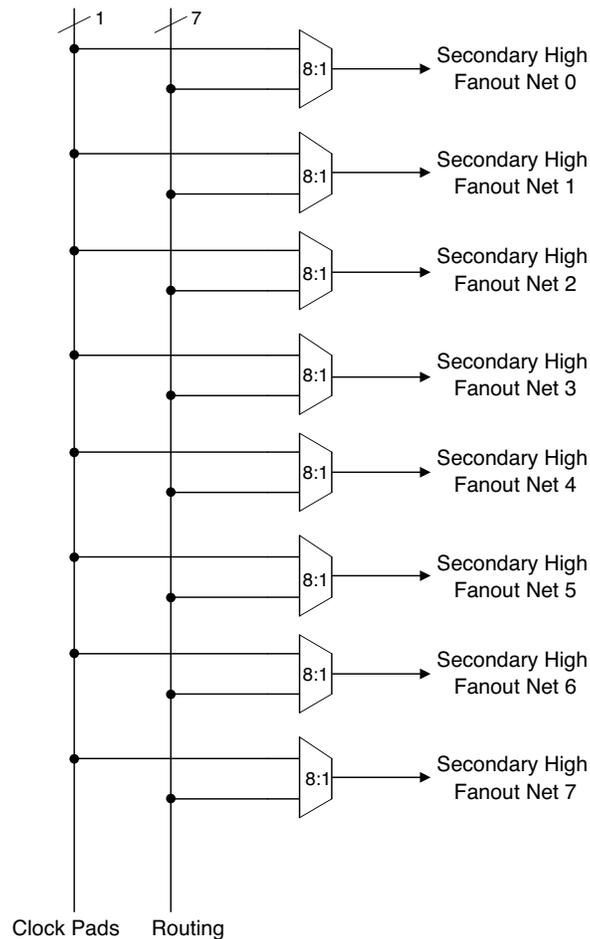
The Lattice design tools support the creation of a variety of different size memories. Where appropriate, the software will construct these using distributed memory primitives that represent the capabilities of the PFU. Table 2-3 shows the number of slices required to implement different distributed RAM primitives. For more information about using RAM in MachXO2 devices, please see TN1201, [Memory Usage Guide for MachXO2 Devices](#).

Table 2-3. Number of Slices Required For Implementing Distributed RAM

	SPR 16x4	PDPR 16x4
Number of slices	3	3

Note: SPR = Single Port RAM, PDPR = Pseudo Dual Port RAM

Figure 2-6. Secondary High Fanout Nets for MachXO2 Devices



sysCLOCK Phase Locked Loops (PLLs)

The sysCLOCK PLLs provide the ability to synthesize clock frequencies. The MachXO2-640U, MachXO2-1200/U and larger devices have one or more sysCLOCK PLL. CLKI is the reference frequency input to the PLL and its source can come from an external I/O pin or from internal routing. CLKFB is the feedback signal to the PLL which can come from internal routing or an external I/O pin. The feedback divider is used to multiply the reference frequency and thus synthesize a higher frequency clock output.

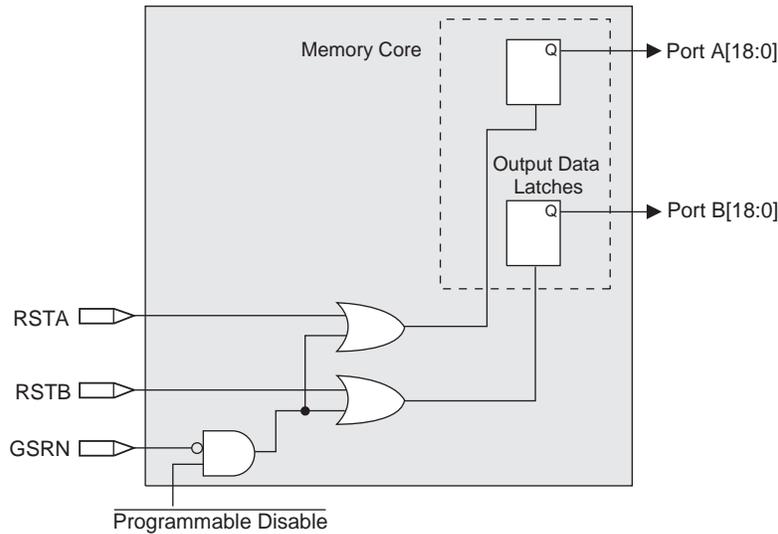
The MachXO2 sysCLOCK PLLs support high resolution (16-bit) fractional-N synthesis. Fractional-N frequency synthesis allows the user to generate an output clock which is a non-integer multiple of the input frequency. For more information about using the PLL with Fractional-N synthesis, please see TN1199, [MachXO2 sysCLOCK PLL Design and Usage Guide](#).

Each output has its own output divider, thus allowing the PLL to generate different frequencies for each output. The output dividers can have a value from 1 to 128. The output dividers may also be cascaded together to generate low frequency clocks. The CLKOP, CLKOS, CLKOS2, and CLKOS3 outputs can all be used to drive the MachXO2 clock distribution network directly or general purpose routing resources can be used.

The LOCK signal is asserted when the PLL determines it has achieved lock and de-asserted if a loss of lock is detected. A block diagram of the PLL is shown in Figure 2-7.

The setup and hold times of the device can be improved by programming a phase shift into the CLKOS, CLKOS2, and CLKOS3 output clocks which will advance or delay the output clock with reference to the CLKOP output clock.

Figure 2-9. Memory Core Reset

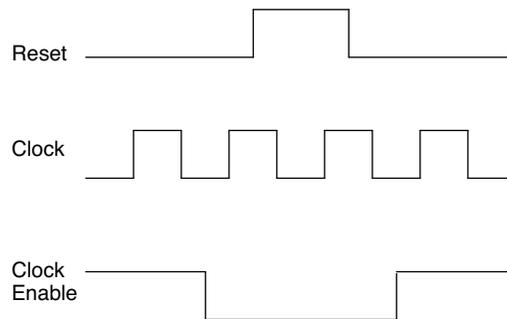


For further information on the sysMEM EBR block, please refer to TN1201, [Memory Usage Guide for MachXO2 Devices](#).

EBR Asynchronous Reset

EBR asynchronous reset or GSR (if used) can only be applied if all clock enables are low for a clock cycle before the reset is applied and released a clock cycle after the reset is released, as shown in Figure 2-10. The GSR input to the EBR is always asynchronous.

Figure 2-10. EBR Asynchronous Reset (Including GSR) Timing Diagram



If all clock enables remain enabled, the EBR asynchronous reset or GSR may only be applied and released after the EBR read and write clock inputs are in a steady state condition for a minimum of $1/f_{MAX}$ (EBR clock). The reset release must adhere to the EBR synchronous reset setup time before the next active read or write clock edge.

If an EBR is pre-loaded during configuration, the GSR input must be disabled or the release of the GSR during device wake up must occur before the release of the device I/Os becoming active.

These instructions apply to all EBR RAM, ROM and FIFO implementations. For the EBR FIFO mode, the GSR signal is always enabled and the WE and RE signals act like the clock enable signals in Figure 2-10. The reset timing rules apply to the RPRReset input versus the RE input and the RST input versus the WE and RE inputs. Both RST and RPRReset are always asynchronous EBR inputs. For more details refer to TN1201, [Memory Usage Guide for MachXO2 Devices](#).

Note that there are no reset restrictions if the EBR synchronous reset is used and the EBR GSR input is disabled.

More information on the input gearbox is available in TN1203, [Implementing High-Speed Interfaces with MachXO2 Devices](#).

Output Gearbox

Each PIC on the top edge has a built-in 8:1 output gearbox. Each of these output gearboxes may be programmed as a 7:1 serializer or as one ODDR4 (8:1) gearbox or as two ODDR2 (4:1) gearboxes. Table 2-10 shows the gearbox signals.

Table 2-10. Output Gearbox Signal List

Name	I/O Type	Description
Q	Output	High-speed data output
D[7:0]	Input	Low-speed data from device core
Video TX(7:1): D[6:0]		
GDDR4(8:1): D[7:0]		
GDDR2(4:1)(IOL-A): D[3:0]		
GDDR2(4:1)(IOL-C): D[7:4]		
SCLK	Input	Slow-speed system clock
ECLK [1:0]	Input	High-speed edge clock
RST	Input	Reset

The gearboxes have three stage pipeline registers. The first stage registers sample the low-speed input data on the low-speed system clock. The second stage registers transfer data from the low-speed clock registers to the high-speed clock registers. The third stage pipeline registers controlled by high-speed edge clock shift and mux the high-speed data out to the sysIO buffer. Figure 2-17 shows the output gearbox block diagram.

There are some limitations on the use of the hardened user SPI. These are defined in the following technical notes:

- TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#) (Appendix B)
- TN1205, [Using User Flash Memory and Hardened Control Functions in MachXO2 Devices](#)

Figure 2-22. SPI Core Block Diagram

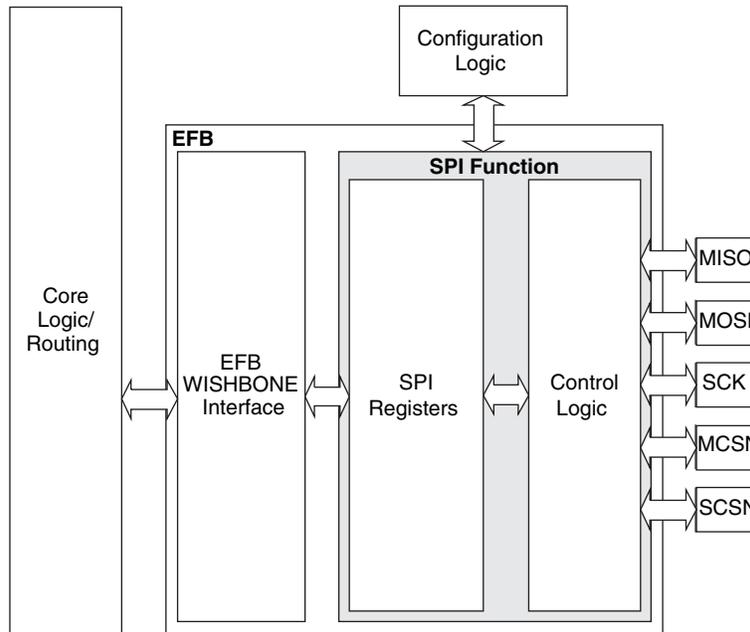


Table 2-16 describes the signals interfacing with the SPI cores.

Table 2-16. SPI Core Signal Description

Signal Name	I/O	Master/Slave	Description
spi_csn[0]	O	Master	SPI master chip-select output
spi_csn[1..7]	O	Master	Additional SPI chip-select outputs (total up to eight slaves)
spi_scsn	I	Slave	SPI slave chip-select input
spi_irq	O	Master/Slave	Interrupt request
spi_clk	I/O	Master/Slave	SPI clock. Output in master mode. Input in slave mode.
spi_miso	I/O	Master/Slave	SPI data. Input in master mode. Output in slave mode.
spi_mosi	I/O	Master/Slave	SPI data. Output in master mode. Input in slave mode.
ufm_sn	I	Slave	Configuration Slave Chip Select (active low), dedicated for selecting the User Flash Memory (UFM).
cfg_stdbby	O	Master/Slave	Stand-by signal – To be connected only to the power module of the MachXO2 device. The signal is enabled only if the “Wakeup Enable” feature has been set within the EFB GUI, SPI Tab.
cfg_wake	O	Master/Slave	Wake-up signal – To be connected only to the power module of the MachXO2 device. The signal is enabled only if the “Wakeup Enable” feature has been set within the EFB GUI, SPI Tab.

Table 2-18. MachXO2 Power Saving Features Description

Device Subsystem	Feature Description
Bandgap	The bandgap can be turned off in standby mode. When the Bandgap is turned off, analog circuitry such as the POR, PLLs, on-chip oscillator, and referenced and differential I/O buffers are also turned off. Bandgap can only be turned off for 1.2 V devices.
Power-On-Reset (POR)	The POR can be turned off in standby mode. This monitors V _{CC} levels. In the event of unsafe V _{CC} drops, this circuit reconfigures the device. When the POR circuitry is turned off, limited power detector circuitry is still active. This option is only recommended for applications in which the power supply rails are reliable.
On-Chip Oscillator	The on-chip oscillator has two power saving features. It may be switched off if it is not needed in your design. It can also be turned off in Standby mode.
PLL	Similar to the on-chip oscillator, the PLL also has two power saving features. It can be statically switched off if it is not needed in a design. It can also be turned off in Standby mode. The PLL will wait until all output clocks from the PLL are driven low before powering off.
I/O Bank Controller	Referenced and differential I/O buffers (used to implement standards such as HSTL, SSTL and LVDS) consume more than ratioed single-ended I/Os such as LVCMOS and LVTTTL. The I/O bank controller allows the user to turn these I/Os off dynamically on a per bank selection.
Dynamic Clock Enable for Primary Clock Nets	Each primary clock net can be dynamically disabled to save power.
Power Guard	Power Guard is a feature implemented in input buffers. This feature allows users to switch off the input buffer when it is not needed. This feature can be used in both clock and data paths. Its biggest impact is that in the standby mode it can be used to switch off clock inputs that are distributed using general routing resources.

For more details on the standby mode refer to TN1198, [Power Estimation and Management for MachXO2 Devices](#).

Power On Reset

MachXO2 devices have power-on reset circuitry to monitor V_{CCINT} and V_{CCIO} voltage levels during power-up and operation. At power-up, the POR circuitry monitors V_{CCINT} and V_{CCIO0} (controls configuration) voltage levels. It then triggers download from the on-chip configuration Flash memory after reaching the V_{PORUP} level specified in the Power-On-Reset Voltage table in the DC and Switching Characteristics section of this data sheet. For devices without voltage regulators (ZE and HE devices), V_{CCINT} is the same as the V_{CC} supply voltage. For devices with voltage regulators (HC devices), V_{CCINT} is regulated from the V_{CC} supply voltage. From this voltage reference, the time taken for configuration and entry into user mode is specified as Flash Download Time (t_{REFRESH}) in the DC and Switching Characteristics section of this data sheet. Before and during configuration, the I/Os are held in tri-state. I/Os are released to user functionality once the device has finished configuration. Note that for HC devices, a separate POR circuit monitors external V_{CC} voltage in addition to the POR circuit that monitors the internal post-regulated power supply voltage level.

Once the device enters into user mode, the POR circuitry can optionally continue to monitor V_{CCINT} levels. If V_{CCINT} drops below V_{PORDNBG} level (with the bandgap circuitry switched on) or below V_{PORDNSRAM} level (with the bandgap circuitry switched off to conserve power) device functionality cannot be guaranteed. In such a situation the POR issues a reset and begins monitoring the V_{CCINT} and V_{CCIO} voltage levels. V_{PORDNBG} and V_{PORDNSRAM} are both specified in the Power-On-Reset Voltage table in the DC and Switching Characteristics section of this data sheet.

Note that once a ZE or HE device enters user mode, users can switch off the bandgap to conserve power. When the bandgap circuitry is switched off, the POR circuitry also shuts down. The device is designed such that a minimal, low power POR circuit is still operational (this corresponds to the V_{PORDNSRAM} reset point described in the paragraph above). However this circuit is not as accurate as the one that operates when the bandgap is switched on. The low power POR circuit emulates an SRAM cell and is biased to trip before the vast majority of SRAM cells flip. If users are concerned about the V_{CC} supply dropping below V_{CC} (min) they should not shut down the bandgap or POR circuit.

Configuration and Testing

This section describes the configuration and testing features of the MachXO2 family.

IEEE 1149.1-Compliant Boundary Scan Testability

All MachXO2 devices have boundary scan cells that are accessed through an IEEE 1149.1 compliant test access port (TAP). This allows functional testing of the circuit board, on which the device is mounted, through a serial scan path that can access all critical logic nodes. Internal registers are linked internally, allowing test data to be shifted in and loaded directly onto test nodes, or test data to be captured and shifted out for verification. The test access port consists of dedicated I/Os: TDI, TDO, TCK and TMS. The test access port shares its power supply with V_{CCIO} Bank 0 and can operate with LVCMOS3.3, 2.5, 1.8, 1.5, and 1.2 standards.

For more details on boundary scan test, see AN8066, [Boundary Scan Testability with Lattice sysIO Capability](#) and TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#).

Device Configuration

All MachXO2 devices contain two ports that can be used for device configuration. The Test Access Port (TAP), which supports bit-wide configuration and the sysCONFIG port which supports serial configuration through I²C or SPI. The TAP supports both the IEEE Standard 1149.1 Boundary Scan specification and the IEEE Standard 1532 In-System Configuration specification. There are various ways to configure a MachXO2 device:

1. Internal Flash Download
2. JTAG
3. Standard Serial Peripheral Interface (Master SPI mode) – interface to boot PROM memory
4. System microprocessor to drive a serial slave SPI port (SSPI mode)
5. Standard I²C Interface to system microprocessor

Upon power-up, the configuration SRAM is ready to be configured using the selected sysCONFIG port. Once a configuration port is selected, it will remain active throughout that configuration cycle. The IEEE 1149.1 port can be activated any time after power-up by sending the appropriate command through the TAP port. Optionally the device can run a CRC check upon entering the user mode. This will ensure that the device was configured correctly.

The sysCONFIG port has 10 dual-function pins which can be used as general purpose I/Os if they are not required for configuration. See TN1204, [MachXO2 Programming and Configuration Usage Guide](#) for more information about using the dual-use pins as general purpose I/Os.

Lattice design software uses proprietary compression technology to compress bit-streams for use in MachXO2 devices. Use of this technology allows Lattice to provide a lower cost solution. In the unlikely event that this technology is unable to compress bitstreams to fit into the amount of on-chip Flash memory, there are a variety of techniques that can be utilized to allow the bitstream to fit in the on-chip Flash memory. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

The Test Access Port (TAP) has five dual purpose pins (TDI, TDO, TMS, TCK and JTAGENB). These pins are dual function pins - TDI, TDO, TMS and TCK can be used as general purpose I/O if desired. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

TransFR (Transparent Field Reconfiguration)

TransFR is a unique Lattice technology that allows users to update their logic in the field without interrupting system operation using a simple push-button solution. For more details refer to TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#) for details.

Power-On-Reset Voltage Levels^{1, 2, 3, 4, 5}

Symbol	Parameter	Min.	Typ.	Max.	Units
V _{PORUP}	Power-On-Reset ramp up trip point (band gap based circuit monitoring V _{CCINT} and V _{CCIO0})	0.9	—	1.06	V
V _{PORUPEXT}	Power-On-Reset ramp up trip point (band gap based circuit monitoring external V _{CC} power supply)	1.5	—	2.1	V
V _{PORDNBG}	Power-On-Reset ramp down trip point (band gap based circuit monitoring V _{CCINT})	0.75	—	0.93	V
V _{PORDNBGEXT}	Power-On-Reset ramp down trip point (band gap based circuit monitoring V _{CC})	0.98	—	1.33	V
V _{PORDNSRAM}	Power-On-Reset ramp down trip point (SRAM based circuit monitoring V _{CCINT})	—	0.6	—	V
V _{PORDNSRAMEXT}	Power-On-Reset ramp down trip point (SRAM based circuit monitoring V _{CC})	—	0.96	—	V

1. These POR trip points are only provided for guidance. Device operation is only characterized for power supply voltages specified under recommended operating conditions.
2. For devices without voltage regulators V_{CCINT} is the same as the V_{CC} supply voltage. For devices with voltage regulators, V_{CCINT} is regulated from the V_{CC} supply voltage.
3. Note that V_{PORUP} (min.) and V_{PORDNBG} (max.) are in different process corners. For any given process corner V_{PORDNBG} (max.) is always 12.0 mV below V_{PORUP} (min.).
4. V_{PORUPEXT} is for HC devices only. In these devices a separate POR circuit monitors the external V_{CC} power supply.
5. V_{CCIO0} does not have a Power-On-Reset ramp down trip point. V_{CCIO0} must remain within the Recommended Operating Conditions to ensure proper operation.

Programming/Erase Specifications

Symbol	Parameter	Min.	Max. ¹	Units
N _{PROGCYC}	Flash Programming cycles per t _{RETENTION}	—	10,000	Cycles
	Flash functional programming cycles	—	100,000	
t _{RETENTION}	Data retention at 100 °C junction temperature	10	—	Years
	Data retention at 85 °C junction temperature	20	—	

1. Maximum Flash memory reads are limited to 7.5E13 cycles over the lifetime of the product.

Hot Socketing Specifications^{1, 2, 3}

Symbol	Parameter	Condition	Max.	Units
I _{DK}	Input or I/O leakage Current	0 < V _{IN} < V _{IH} (MAX)	+/-1000	μA

1. Insensitive to sequence of V_{CC} and V_{CCIO}. However, assumes monotonic rise/fall rates for V_{CC} and V_{CCIO}.
2. 0 < V_{CC} < V_{CC} (MAX), 0 < V_{CCIO} < V_{CCIO} (MAX).
3. I_{DK} is additive to I_{PU}, I_{PD} or I_{BH}.

ESD Performance

Please refer to the [MachXO2 Product Family Qualification Summary](#) for complete qualification data, including ESD performance.

Programming and Erase Flash Supply Current – ZE Devices^{1, 2, 3, 4}

Symbol	Parameter	Device	Typ. ⁵	Units
I _{CC}	Core Power Supply	LCMXO2-256ZE	13	mA
		LCMXO2-640ZE	14	mA
		LCMXO2-1200ZE	15	mA
		LCMXO2-2000ZE	17	mA
		LCMXO2-4000ZE	18	mA
		LCMXO2-7000ZE	20	mA
I _{CCIO}	Bank Power Supply ⁶	All devices	0	mA

1. For further information on supply current, please refer to TN1198, [Power Estimation and Management for MachXO2 Devices](#).

2. Assumes all inputs are held at V_{CCIO} or GND and all outputs are tri-stated.

3. Typical user pattern.

4. JTAG programming is at 25 MHz.

5. T_J = 25 °C, power supplies at nominal voltage.

6. Per bank. V_{CCIO} = 2.5 V. Does not include pull-up/pull-down.

Parameter	Description	Device	-3		-2		-1		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
t _{SU_DEL}	Clock to Data Setup – PIO Input Register with Data Input Delay	MachXO2-256ZE	2.62	—	2.91	—	3.14	—	ns
		MachXO2-640ZE	2.56	—	2.85	—	3.08	—	ns
		MachXO2-1200ZE	2.30	—	2.57	—	2.79	—	ns
		MachXO2-2000ZE	2.25	—	2.50	—	2.70	—	ns
		MachXO2-4000ZE	2.39	—	2.60	—	2.76	—	ns
		MachXO2-7000ZE	2.17	—	2.33	—	2.43	—	ns
t _{H_DEL}	Clock to Data Hold – PIO Input Register with Input Data Delay	MachXO2-256ZE	-0.44	—	-0.44	—	-0.44	—	ns
		MachXO2-640ZE	-0.43	—	-0.43	—	-0.43	—	ns
		MachXO2-1200ZE	-0.28	—	-0.28	—	-0.28	—	ns
		MachXO2-2000ZE	-0.31	—	-0.31	—	-0.31	—	ns
		MachXO2-4000ZE	-0.34	—	-0.34	—	-0.34	—	ns
		MachXO2-7000ZE	-0.21	—	-0.21	—	-0.21	—	ns
f _{MAX_IO}	Clock Frequency of I/O and PFU Register	All MachXO2 devices	—	150	—	125	—	104	MHz
General I/O Pin Parameters (Using Edge Clock without PLL)									
t _{COE}	Clock to Output – PIO Output Register	MachXO2-1200ZE	—	11.10	—	11.51	—	11.91	ns
		MachXO2-2000ZE	—	11.10	—	11.51	—	11.91	ns
		MachXO2-4000ZE	—	10.89	—	11.28	—	11.67	ns
		MachXO2-7000ZE	—	11.10	—	11.51	—	11.91	ns
t _{SUE}	Clock to Data Setup – PIO Input Register	MachXO2-1200ZE	-0.23	—	-0.23	—	-0.23	—	ns
		MachXO2-2000ZE	-0.23	—	-0.23	—	-0.23	—	ns
		MachXO2-4000ZE	-0.15	—	-0.15	—	-0.15	—	ns
		MachXO2-7000ZE	-0.23	—	-0.23	—	-0.23	—	ns
t _{HE}	Clock to Data Hold – PIO Input Register	MachXO2-1200ZE	3.81	—	4.11	—	4.52	—	ns
		MachXO2-2000ZE	3.81	—	4.11	—	4.52	—	ns
		MachXO2-4000ZE	3.60	—	3.89	—	4.28	—	ns
		MachXO2-7000ZE	3.81	—	4.11	—	4.52	—	ns
t _{SU_DELE}	Clock to Data Setup – PIO Input Register with Data Input Delay	MachXO2-1200ZE	2.78	—	3.11	—	3.40	—	ns
		MachXO2-2000ZE	2.78	—	3.11	—	3.40	—	ns
		MachXO2-4000ZE	3.11	—	3.48	—	3.79	—	ns
		MachXO2-7000ZE	2.94	—	3.30	—	3.60	—	ns
t _{H_DELE}	Clock to Data Hold – PIO Input Register with Input Data Delay	MachXO2-1200ZE	-0.29	—	-0.29	—	-0.29	—	ns
		MachXO2-2000ZE	-0.29	—	-0.29	—	-0.29	—	ns
		MachXO2-4000ZE	-0.46	—	-0.46	—	-0.46	—	ns
		MachXO2-7000ZE	-0.37	—	-0.37	—	-0.37	—	ns
General I/O Pin Parameters (Using Primary Clock with PLL)									
t _{COPLL}	Clock to Output – PIO Output Register	MachXO2-1200ZE	—	7.95	—	8.07	—	8.19	ns
		MachXO2-2000ZE	—	7.97	—	8.10	—	8.22	ns
		MachXO2-4000ZE	—	7.98	—	8.10	—	8.23	ns
		MachXO2-7000ZE	—	8.02	—	8.14	—	8.26	ns
t _{SUPLL}	Clock to Data Setup – PIO Input Register	MachXO2-1200ZE	0.85	—	0.85	—	0.89	—	ns
		MachXO2-2000ZE	0.84	—	0.84	—	0.86	—	ns
		MachXO2-4000ZE	0.84	—	0.84	—	0.85	—	ns
		MachXO2-7000ZE	0.83	—	0.83	—	0.81	—	ns

Figure 3-5. Receiver RX.CLK.Aligned and MEM DDR Input Waveforms

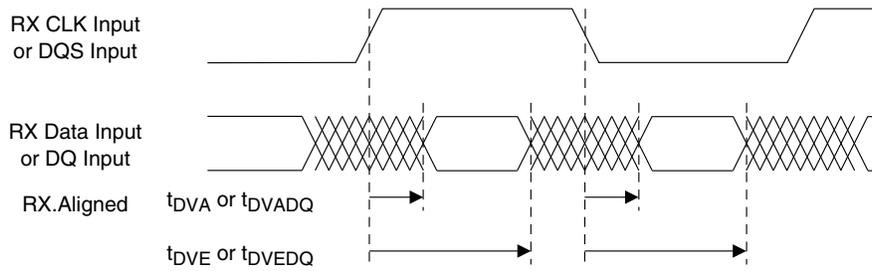


Figure 3-6. Receiver RX.CLK.Centered Waveforms

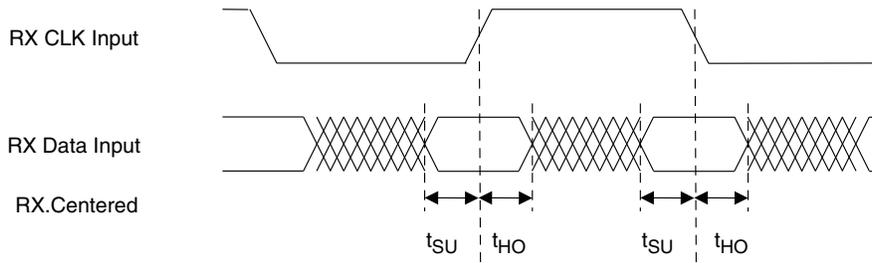


Figure 3-7. Transmitter TX.CLK.Aligned Waveforms

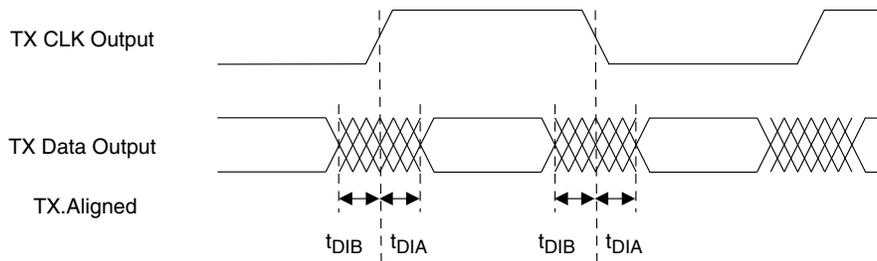
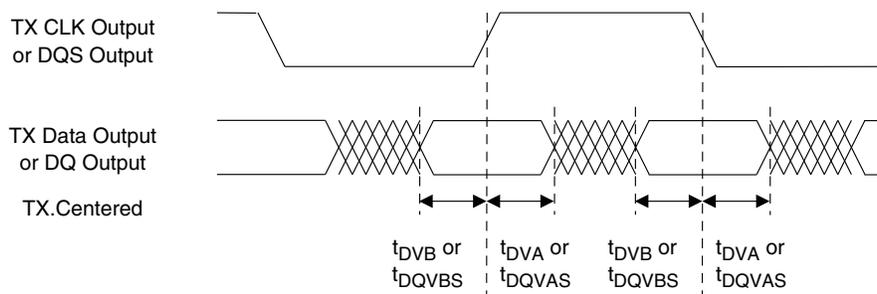


Figure 3-8. Transmitter TX.CLK.Centered and MEM DDR Output Waveforms



sysCLOCK PLL Timing

Over Recommended Operating Conditions

Parameter	Descriptions	Conditions	Min.	Max.	Units
f_{IN}	Input Clock Frequency (CLKI, CLKFB)		7	400	MHz
f_{OUT}	Output Clock Frequency (CLKOP, CLKOS, CLKOS2)		1.5625	400	MHz
f_{OUT2}	Output Frequency (CLKOS3 cascaded from CLKOS2)		0.0122	400	MHz
f_{VCO}	PLL VCO Frequency		200	800	MHz
f_{PFD}	Phase Detector Input Frequency		7	400	MHz
AC Characteristics					
t_{DT}	Output Clock Duty Cycle	Without duty trim selected ³	45	55	%
$t_{DT_TRIM}^7$	Edge Duty Trim Accuracy		-75	75	%
t_{PH}^4	Output Phase Accuracy		-6	6	%
$t_{OPJIT}^{1,8}$	Output Clock Period Jitter	$f_{OUT} > 100$ MHz	—	150	ps p-p
		$f_{OUT} < 100$ MHz	—	0.007	UIPP
	Output Clock Cycle-to-cycle Jitter	$f_{OUT} > 100$ MHz	—	180	ps p-p
		$f_{OUT} < 100$ MHz	—	0.009	UIPP
	Output Clock Phase Jitter	$f_{PFD} > 100$ MHz	—	160	ps p-p
		$f_{PFD} < 100$ MHz	—	0.011	UIPP
	Output Clock Period Jitter (Fractional-N)	$f_{OUT} > 100$ MHz	—	230	ps p-p
		$f_{OUT} < 100$ MHz	—	0.12	UIPP
Output Clock Cycle-to-cycle Jitter (Fractional-N)	$f_{OUT} > 100$ MHz	—	230	ps p-p	
	$f_{OUT} < 100$ MHz	—	0.12	UIPP	
t_{SPO}	Static Phase Offset	Divider ratio = integer	-120	120	ps
t_W	Output Clock Pulse Width	At 90% or 10% ³	0.9	—	ns
$t_{LOCK}^{2,5}$	PLL Lock-in Time		—	15	ms
t_{UNLOCK}	PLL Unlock Time		—	50	ns
t_{IPJIT}^6	Input Clock Period Jitter	$f_{PFD} \geq 20$ MHz	—	1,000	ps p-p
		$f_{PFD} < 20$ MHz	—	0.02	UIPP
t_{HI}	Input Clock High Time	90% to 90%	0.5	—	ns
t_{LO}	Input Clock Low Time	10% to 10%	0.5	—	ns
t_{STABLE}^5	STANDBY High to PLL Stable		—	15	ms
t_{RST}	RST/RESETM Pulse Width		1	—	ns
t_{RSTREC}	RST Recovery Time		1	—	ns
t_{RST_DIV}	RESETC/D Pulse Width		10	—	ns
t_{RSTREC_DIV}	RESETC/D Recovery Time		1	—	ns
$t_{ROTATE-SETUP}$	PHASESTEP Setup Time		10	—	ns

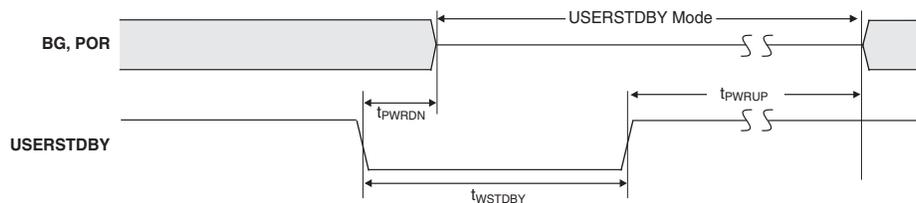
MachXO2 Oscillator Output Frequency

Symbol	Parameter	Min.	Typ.	Max	Units
f _{MAX}	Oscillator Output Frequency (Commercial Grade Devices, 0 to 85°C)	125.685	133	140.315	MHz
	Oscillator Output Frequency (Industrial Grade Devices, -40 °C to 100 °C)	124.355	133	141.645	MHz
t _{DT}	Output Clock Duty Cycle	43	50	57	%
t _{OPJIT} ¹	Output Clock Period Jitter	0.01	0.012	0.02	UIPP
t _{STABLEOSC}	STDBY Low to Oscillator Stable	0.01	0.05	0.1	µs

1. Output Clock Period Jitter specified at 133 MHz. The values for lower frequencies will be smaller UIPP. The typical value for 133 MHz is 95 ps and for 2.08 MHz the typical value is 1.54 ns.

MachXO2 Standby Mode Timing – HC/HE Devices

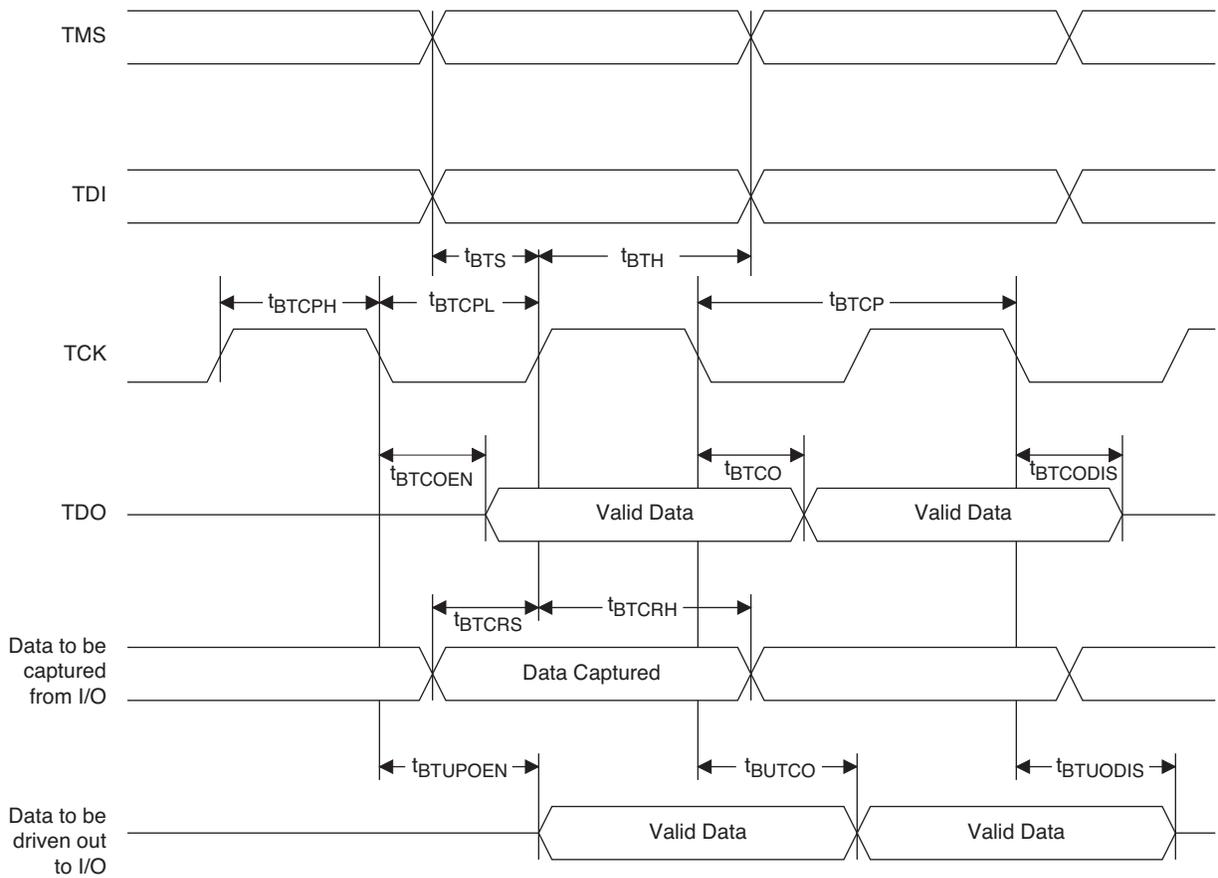
Symbol	Parameter	Device	Min.	Typ.	Max	Units
t _{PWRDN}	USERSTDBY High to Stop	All	—	—	9	ns
t _{PWRUP}	USERSTDBY Low to Power Up	LCMXO2-256		—		µs
		LCMXO2-640		—		µs
		LCMXO2-640U		—		µs
		LCMXO2-1200	20	—	50	µs
		LCMXO2-1200U		—		µs
		LCMXO2-2000		—		µs
		LCMXO2-2000U		—		µs
		LCMXO2-4000		—		µs
LCMXO2-7000		—		µs		
t _{WSTDBY}	USERSTDBY Pulse Width	All	18	—	—	ns



MachXO2 Standby Mode Timing – ZE Devices

Symbol	Parameter	Device	Min.	Typ.	Max	Units
t _{PWRDN}	USERSTDBY High to Stop	All	—	—	13	ns
t _{PWRUP}	USERSTDBY Low to Power Up	LCMXO2-256		—		µs
		LCMXO2-640		—		µs
		LCMXO2-1200	20	—	50	µs
		LCMXO2-2000		—		µs
		LCMXO2-4000		—		µs
		LCMXO2-7000		—		µs
t _{WSTDBY}	USERSTDBY Pulse Width	All	19	—	—	ns
t _{BNDGAPSTBL}	USERSTDBY High to Bandgap Stable	All	—	—	15	ns

Figure 3-12. JTAG Port Timing Waveforms



	MachXO2-1200					MachXO2-1200U
	100 TQFP	132 csBGA	144 TQFP	25 WLCSP	32 QFN ¹	256 ftBGA
General Purpose I/O per Bank						
Bank 0	18	25	27	11	9	50
Bank 1	21	26	26	0	2	52
Bank 2	20	28	28	7	9	52
Bank 3	20	25	26	0	2	16
Bank 4	0	0	0	0	0	16
Bank 5	0	0	0	0	0	20
Total General Purpose Single Ended I/O	79	104	107	18	22	206
Differential I/O per Bank						
Bank 0	9	13	14	5	4	25
Bank 1	10	13	13	0	1	26
Bank 2	10	14	14	2	4	26
Bank 3	10	12	13	0	1	8
Bank 4	0	0	0	0	0	8
Bank 5	0	0	0	0	0	10
Total General Purpose Differential I/O	39	52	54	7	10	103
Dual Function I/O						
	31	33	33	18	22	33
High-speed Differential I/O						
Bank 0	4	7	7	0	0	14
Gearboxes						
Number of 7:1 or 8:1 Output Gearbox Available (Bank 0)	4	7	7	0	0	14
Number of 7:1 or 8:1 Input Gearbox Available (Bank 2)	5	7	7	0	2	14
DQS Groups						
Bank 1	1	2	2	0	0	2
VCCIO Pins						
Bank 0	2	3	3	1	2	4
Bank 1	2	3	3	0	1	4
Bank 2	2	3	3	1	2	4
Bank 3	3	3	3	0	1	1
Bank 4	0	0	0	0	0	2
Bank 5	0	0	0	0	0	1
VCC	2	4	4	2	2	8
GND	8	10	12	2	2	24
NC	1	1	8	0	0	1
Reserved for Configuration	1	1	1	1	1	1
Total Count of Bonded Pins	100	132	144	25	32	256

1. Lattice recommends soldering the central thermal pad onto the top PCB ground for improved thermal resistance.

For Further Information

For further information regarding logic signal connections for various packages please refer to the MachXO2 Device Pinout Files.

Thermal Management

Thermal management is recommended as part of any sound FPGA design methodology. To assess the thermal characteristics of a system, Lattice specifies a maximum allowable junction temperature in all device data sheets. Users must complete a thermal analysis of their specific design to ensure that the device and package do not exceed the junction temperature limits. Refer to the Thermal Management document to find the device/package specific thermal values.

For Further Information

For further information regarding Thermal Management, refer to the following:

- [Thermal Management](#) document
- TN1198, [Power Estimation and Management for MachXO2 Devices](#)
- The Power Calculator tool is included with the Lattice design tools, or as a standalone download from www.latticesemi.com/software

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200HC-4SG32I	1280	2.5 V / 3.3 V	-4	Halogen-Free QFN	32	IND
LCMXO2-1200HC-5SG32I	1280	2.5 V / 3.3 V	-5	Halogen-Free QFN	32	IND
LCMXO2-1200HC-6SG32I	1280	2.5 V / 3.3 V	-6	Halogen-Free QFN	32	IND
LCMXO2-1200HC-4TG100I	1280	2.5 V / 3.3 V	-4	Halogen-Free TQFP	100	IND
LCMXO2-1200HC-5TG100I	1280	2.5 V / 3.3 V	-5	Halogen-Free TQFP	100	IND
LCMXO2-1200HC-6TG100I	1280	2.5 V / 3.3 V	-6	Halogen-Free TQFP	100	IND
LCMXO2-1200HC-4MG132I	1280	2.5 V / 3.3 V	-4	Halogen-Free csBGA	132	IND
LCMXO2-1200HC-5MG132I	1280	2.5 V / 3.3 V	-5	Halogen-Free csBGA	132	IND
LCMXO2-1200HC-6MG132I	1280	2.5 V / 3.3 V	-6	Halogen-Free csBGA	132	IND
LCMXO2-1200HC-4TG144I	1280	2.5 V / 3.3 V	-4	Halogen-Free TQFP	144	IND
LCMXO2-1200HC-5TG144I	1280	2.5 V / 3.3 V	-5	Halogen-Free TQFP	144	IND
LCMXO2-1200HC-6TG144I	1280	2.5 V / 3.3 V	-6	Halogen-Free TQFP	144	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200UHC-4FTG256I	1280	2.5 V / 3.3 V	-4	Halogen-Free ftBGA	256	IND
LCMXO2-1200UHC-5FTG256I	1280	2.5 V / 3.3 V	-5	Halogen-Free ftBGA	256	IND
LCMXO2-1200UHC-6FTG256I	1280	2.5 V / 3.3 V	-6	Halogen-Free ftBGA	256	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000HC-4TG100I	2112	2.5 V / 3.3 V	-4	Halogen-Free TQFP	100	IND
LCMXO2-2000HC-5TG100I	2112	2.5 V / 3.3 V	-5	Halogen-Free TQFP	100	IND
LCMXO2-2000HC-6TG100I	2112	2.5 V / 3.3 V	-6	Halogen-Free TQFP	100	IND
LCMXO2-2000HC-4MG132I	2112	2.5 V / 3.3 V	-4	Halogen-Free csBGA	132	IND
LCMXO2-2000HC-5MG132I	2112	2.5 V / 3.3 V	-5	Halogen-Free csBGA	132	IND
LCMXO2-2000HC-6MG132I	2112	2.5 V / 3.3 V	-6	Halogen-Free csBGA	132	IND
LCMXO2-2000HC-4TG144I	2112	2.5 V / 3.3 V	-4	Halogen-Free TQFP	144	IND
LCMXO2-2000HC-5TG144I	2112	2.5 V / 3.3 V	-5	Halogen-Free TQFP	144	IND
LCMXO2-2000HC-6TG144I	2112	2.5 V / 3.3 V	-6	Halogen-Free TQFP	144	IND
LCMXO2-2000HC-4BG256I	2112	2.5 V / 3.3 V	-4	Halogen-Free caBGA	256	IND
LCMXO2-2000HC-5BG256I	2112	2.5 V / 3.3 V	-5	Halogen-Free caBGA	256	IND
LCMXO2-2000HC-6BG256I	2112	2.5 V / 3.3 V	-6	Halogen-Free caBGA	256	IND
LCMXO2-2000HC-4FTG256I	2112	2.5 V / 3.3 V	-4	Halogen-Free ftBGA	256	IND
LCMXO2-2000HC-5FTG256I	2112	2.5 V / 3.3 V	-5	Halogen-Free ftBGA	256	IND
LCMXO2-2000HC-6FTG256I	2112	2.5 V / 3.3 V	-6	Halogen-Free ftBGA	256	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000UHC-4FG484I	2112	2.5 V / 3.3 V	-4	Halogen-Free fpBGA	484	IND
LCMXO2-2000UHC-5FG484I	2112	2.5 V / 3.3 V	-5	Halogen-Free fpBGA	484	IND
LCMXO2-2000UHC-6FG484I	2112	2.5 V / 3.3 V	-6	Halogen-Free fpBGA	484	IND

High Performance Industrial Grade Devices Without Voltage Regulator, Halogen Free (RoHS) Packaging

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000HE-4TG100I	2112	1.2 V	-4	Halogen-Free TQFP	100	IND
LCMXO2-2000HE-5TG100I	2112	1.2 V	-5	Halogen-Free TQFP	100	IND
LCMXO2-2000HE-6TG100I	2112	1.2 V	-6	Halogen-Free TQFP	100	IND
LCMXO2-2000HE-4MG132I	2112	1.2 V	-4	Halogen-Free csBGA	132	IND
LCMXO2-2000HE-5MG132I	2112	1.2 V	-5	Halogen-Free csBGA	132	IND
LCMXO2-2000HE-6MG132I	2112	1.2 V	-6	Halogen-Free csBGA	132	IND
LCMXO2-2000HE-4TG144I	2112	1.2 V	-4	Halogen-Free TQFP	144	IND
LCMXO2-2000HE-5TG144I	2112	1.2 V	-5	Halogen-Free TQFP	144	IND
LCMXO2-2000HE-6TG144I	2112	1.2 V	-6	Halogen-Free TQFP	144	IND
LCMXO2-2000HE-4BG256I	2112	1.2 V	-4	Halogen-Free caBGA	256	IND
LCMXO2-2000HE-5BG256I	2112	1.2 V	-5	Halogen-Free caBGA	256	IND
LCMXO2-2000HE-6BG256I	2112	1.2 V	-6	Halogen-Free caBGA	256	IND
LCMXO2-2000HE-4FTG256I	2112	1.2 V	-4	Halogen-Free ftBGA	256	IND
LCMXO2-2000HE-5FTG256I	2112	1.2 V	-5	Halogen-Free ftBGA	256	IND
LCMXO2-2000HE-6FTG256I	2112	1.2 V	-6	Halogen-Free ftBGA	256	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000UHE-4FG484I	2112	1.2 V	-4	Halogen-Free fpBGA	484	IND
LCMXO2-2000UHE-5FG484I	2112	1.2 V	-5	Halogen-Free fpBGA	484	IND
LCMXO2-2000UHE-6FG484I	2112	1.2 V	-6	Halogen-Free fpBGA	484	IND

Date	Version	Section	Change Summary
May 2011	01.3	Multiple	Replaced “SED” with “SRAM CRC Error Detection” throughout the document.
		DC and Switching Characteristics	Added footnote 1 to Program Erase Specifications table.
		Pinout Information	Updated Pin Information Summary tables. Signal name SO/SISPISO changed to SO/SPISO in the Signal Descriptions table.
April 2011	01.2	—	Data sheet status changed from Advance to Preliminary.
		Introduction	Updated MachXO2 Family Selection Guide table.
		Architecture	Updated Supported Input Standards table.
			Updated sysMEM Memory Primitives diagram.
			Added differential SSTL and HSTL IO standards.
		DC and Switching Characteristics	Updates following parameters: POR voltage levels, DC electrical characteristics, static supply current for ZE/HE/HC devices, static power consumption contribution of different components – ZE devices, programming and erase Flash supply current.
			Added VREF specifications to sysIO recommended operating conditions.
			Updating timing information based on characterization.
Ordering Information	Added differential SSTL and HSTL IO standards.		
	Added Ordering Part Numbers for R1 devices, and devices in WLCSP packages. Added R1 device specifications.		
January 2011	01.1	All	Included ultra-high I/O devices.
		DC and Switching Characteristics	Recommended Operating Conditions table – Added footnote 3.
			DC Electrical Characteristics table – Updated data for I_{IL} , I_{IH} , V_{HYST} typical values updated.
			Generic DDRX2 Outputs with Clock and Data Aligned at Pin (GDDR2_TX.ECLK.Aligned) Using PCLK Pin for Clock Input tables – Updated data for T_{DIA} and T_{DIB} .
			Generic DDRX4 Outputs with Clock and Data Aligned at Pin (GDDR4_TX.ECLK.Aligned) Using PCLK Pin for Clock Input tables – Updated data for T_{DIA} and T_{DIB} .
			Power-On-Reset Voltage Levels table - clarified note 3.
			Clarified VCCIO related recommended operating conditions specifications.
			Added power supply ramp rate requirements.
			Added Power Supply Ramp Rates table.
			Updated Programming/Erase Specifications table.
		Removed references to V_{CCP} .	
Pinout Information	Included number of 7:1 and 8:1 gearboxes (input and output) in the pin information summary tables.		
	Removed references to V_{CCP} .		
November 2010	01.0	—	Initial release.